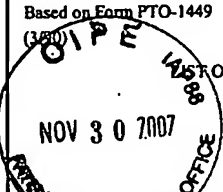


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	APPLICANT Martin Thomas Miller	
	FILING DATE September 29, 2003	GROUP 2117

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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	AI						
	AJ						
	AK						

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							YES	NO
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	APPLICANT Martin MILLER et al.	
	FILING DATE September 29, 2003	GROUP 2117

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	AD	4 964 117	10/1990	Shier, John S.			
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